

An ISO/TS 16949, ISO 9001 and ISO 14001 Certified Company



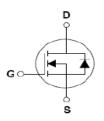






PIN CONFIGURATION

- 1. GATE
- 2. DRAIN
- 3. SOURCE



CDA20N60

TO-3P(N) Plastic Package

| DESCRIPTION | VALUE | UNIT |
|-------------------|-------|------|
| V_{DSS} | 600 | V |
| I _D | 20 | Α |
| $P_{D}(T_{C}=25)$ | 250 | W |

Features

- 1) Fast Switching
- 2) Low ON Resistance(R_{dson}≤0.34Ω)
- 3) Low Gate Charge (Typical Data: 54nC)
- 4) Low Reverse transfer capacitances(Typical: 14.5pF)
- 5) 100% Single Pulse avalanche energy Test

Applications

Power switch circuit of adaptor and charger

Description

CDA20N60, the silicon N-channel Enhanced VDMOSFET, is obtained by the self-aligned planar Technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. The transistor can be used in various power switching circuit for system miniaturization and higher efficiency The package form is TO-3P(N), which accords with the RoHS standard

Absolute Maximum Ratings (Ta=25°C unless otherwise specified)

| DESCRIPTION | SYMBOL | VALUE | UNIT |
|---|-------------------------------|--------------------|------|
| Drain-to-Source Voltage | $V_{	t DSS}$ | 600 | V |
| Continuous Drain Current | - | 20 | Α |
| Continuous Drain Current T _C =100 °C | I _D | 14 | Α |
| Pulsed Drain Current | I _{DM} ^{a1} | 80 | Α |
| Gate-to-Source Voltage | V_{GS} | ±30 | V |
| Single Pulse Avalanche Energy | E _{As} a2 | 550 | mJ |
| Avalanche Energy ,Repetitive | E _{Ar} a1 | 50 | mJ |
| Avalanche Current | l _{AR} a1 | 4.5 | Α |
| Peak Diode Recovery dv/dt | dv/dt ^{a3} | 5.0 | V/ns |
| Power Dissipation | 0 | 250 | W |
| Derating Factor above 25°C | P_D | 2.0 | W/°C |
| Operating Junction and Storage Temperature Ran | $T_{J_{i}}T_{stq}$ | 150°C , –55 to 150 | °C |
| MaximumTemperature for Soldering | T_L | 300 | |

Caution: Stresses greater than those in the "Absolute Maximum Ratings" may cause permanent damage to the device

Thermal Characteristic

| DESCRIPTION | SYMBOL | VALUE | UNIT |
|---|-----------------|-------|------|
| Thermal Resistance, Junction-to-Case | $R_{\theta JC}$ | 0.5 | °C/W |
| Thermal Resistance, Junction-to-Ambient | $R_{\theta JA}$ | 40 | °C/W |



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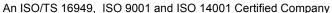


Electrical Characteristics (T_J=25°C unless otherwise specified)

| DESCRIPTION | OVMDOL | Test Conditions | VALUE | | | |
|---|--------------------------------|--|-------|------|------|------|
| | SYMBOL | | Min | Тур | Max | Unit |
| Off Characteristics | | | | | | |
| Drain to Source Breakdown Voltage | $V_{	exttt{DSS}}$ | V_{GS} =0V, I_D =250 μ A | 600 | | | V |
| Bvdss Temperature Coefficient | $\Delta BV_{DSS}/\Delta T_{J}$ | I _D =250uA,Reference25°C | | 0.65 | | V/°C |
| Drain to Source Leakage Current | | V _{DS} =600V, V _{GS} =0V,T _a =25°C | | | 1 | |
| | I _{DSS} | V _{DS} =480V, V _{GS} =0V,T _a =125°C | | | 100 | μA |
| Gate to Source Forward Leakage | $I_{GSS(F)}$ | V _{GS} =+30V | | | 100 | nA |
| Gate to Source Reverse Leakage | $I_{GSS(R)}$ | V _{GS} =-30V | | | -100 | nA |
| | | | | | | |
| ON Characteristics | | 1 | | | | |
| Drain-to-Source On-Resistance | R _{DS(ON} | V_{GS} =10V, I_D =10A | | 0.3 | 0.34 | Ω |
| Gate Threshold Voltage | $V_{GS(TH)}$ | $V_{DS}=V_{GS}$, $I_D=250\mu A$ | 2 | | 4 | V |
| Forward Trans conductance | g_{fs} | V_{DS} =15V, I_{D} =10A | | 17 | | S |
| Note: Pulse width<380µs; duty cycle<2%. | | | | | | |
| Dynamic Characteristics | | | | | | |
| Input Capacitance | C_{iss} | | | 2800 | | pF |
| Output Capacitance | C_{oss} | V _{GS} =0V V _{DS} =25V, f=1.0MHz | | 233 | | |
| Reverse Transfer Capacitance | C_{rss} | | | 14.5 | | |
| Resistive Switching Characteristics | | • | | | | |
| Turn-on Delay Time | t _{d(ON)} | | | 36 | | ns |
| Rise Time | t _r | 1 | | 73 | | |
| Turn-Off Delay Time | t _{d(OFF)} | $I_D = 20A, V_{DD} = 300V, Rg = 25\Omega$ | | 166 | | |
| Fall Time | t _f | 1 - | | 73 | | |
| Total Gate Charge | Q _q | | | 54 | | |
| Gate to Source Charge | Q _{as} | I _D =20A,V _{DD} =300V, VGS=10V | | 16 | | nC |
| Gate to Drain ("Miller")Charge | Q _{ad} | | | 10 | | |
| Source-Drain Diode Characteristics | | | | | | |
| Continuous Source Current (Body Diode) | I _{SD} | | | | 20 | Α |
| Maximum Pulsed Current (Body Diode) | I _{SM} | | | | 80 | Α |
| Diode Forward Voltage | V _{SD} | I _S =12A,V _{GS} =0V | | | 1.5 | V |
| Reverse Recovery Time | t _{rr} | I _S =12A,T _i =25°C | | 595 | | ns |
| Reverse Recovery Charge | Q _{rr} | dI _E /dt=100A/µs,V _{GS} =0V | | 2.9 | | uC |

Notes:

- a1. Repetitive rating; pulse width limited by maximum junction temperature
- a2. L=10mH, I_D =15.5A, Start T_J =25°C
- a3. I_{SD} =20A,di/dt \leq 100A/us, V_{DD} \leq B V_{DS} , Start T_{J} =25°C







Characteristics Curves

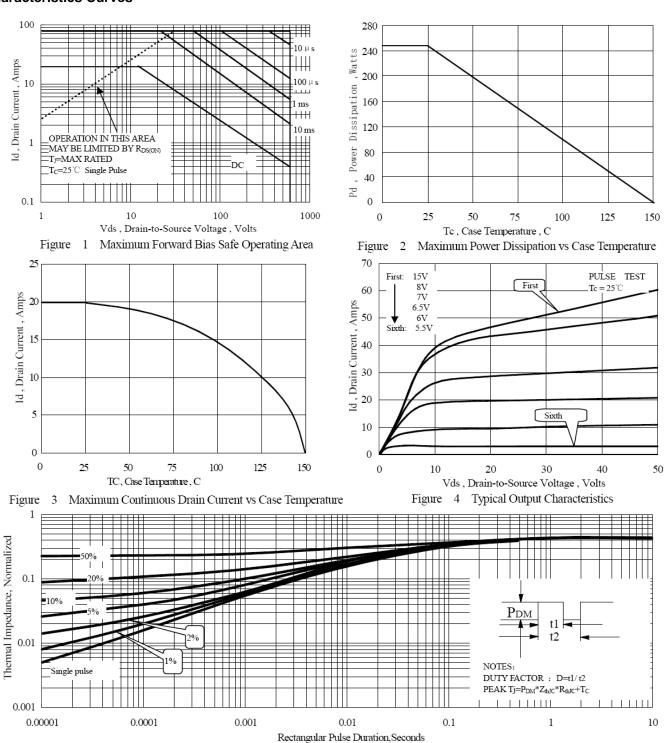
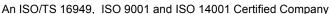


Figure 5 Maximum Effective Thermal Impendance, Junction to Case









Characteristics Curves (cont....)

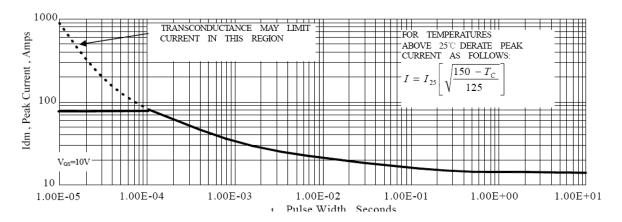


Figure 6 Maximum Peak Current Capability

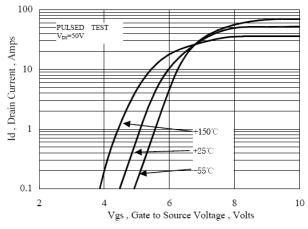
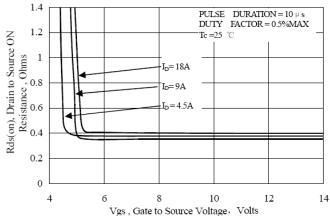


Figure 7 Typical Transfer Characteristics



8 Typical Drain to Source ON Resistance vs Gate Voltage and Drain Current

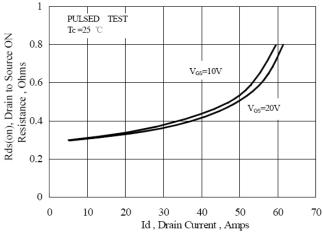
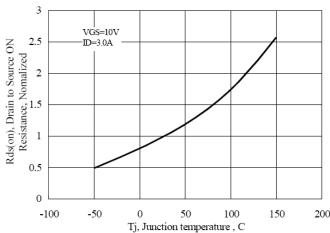
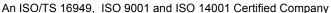


Figure 9 Typical Drain to Source ON Resistance vs Drain Current



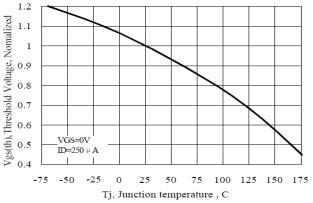
Typical Drian to Source on Resistance Figure 10 vs Junction Temperature



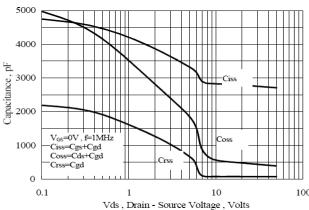




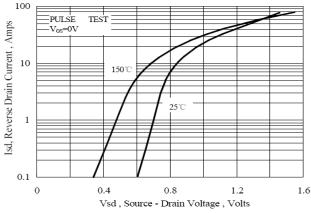
Characteristics Curves (cont....)



11 Typical Theshold Voltage vs Junction Temperature Figure



13 Typical Capacitance vs Drain to Source Voltage Figure



15 Typical Body Diode Transfer Characteristics

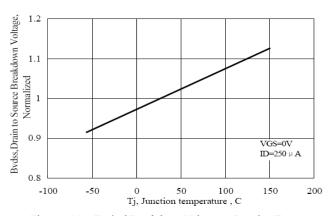


Figure 12 Typical Breakdown Voltage vs Junction Temperature

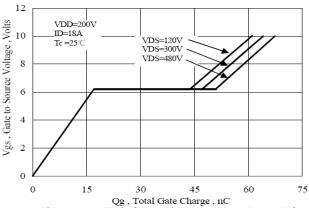
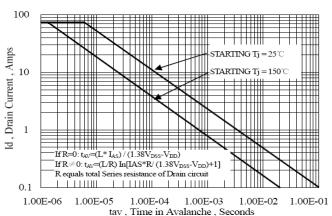


Figure 14 Typical Gate Charge vs Gate to Source Voltage



16 Unclamped Inductive Switching Capability Figure



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Customer Notes

Component Disposal Instructions

- 1. CDIL Semiconductor Devices are RoHS compliant, customers are requested to please dispose as per prevailing Environmental Legislation of their Country.
- 2. In Europe, please dispose as per EU Directive 2002/96/EC on Waste Electrical and Electronic Equipment (WEEE).

Disclaimer

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Continental Device India Pvt. Limited
C-120 Naraina Industrial Area, New Delhi 110 028, India.
Telephone + 91-11-2579 6150, 4141 1112 Fax + 91-11-2579 5290, 4141 1119
email@cdil.com www.cdil.com

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